

<b>Notice of References Cited</b>	Application/Control No. 10/612,129	Applicant(s)/Patent Under Reexamination YEW ET AL.	
	Examiner Phat X. Cao	Art Unit 2814	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,300,812 A	04-1994	Lupinski et al.	257/723
	B	US-6,013,946 A	01-2000	Lee et al.	257/684
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06-029454	04-1994	Japan	Hiroshi	N/A
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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